

HiPerFET™ Power MOSFETs

Single DieMOSFET

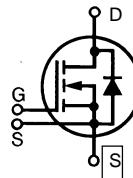
N-Channel Enhancement Mode
Avalanche Rated, High dv/dt, Low t_{rr}

Preliminary data sheet

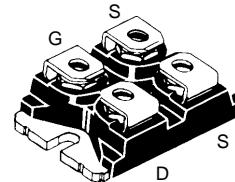
IXFN 34N80

$V_{DSS} = 800 \text{ V}$
 $I_{D25} = 34 \text{ A}$
 $R_{DS(on)} = 0.24 \Omega$

$t_{rr} \leq 250 \text{ ns}$



miniBLOC, SOT-227 B
E153432



G = Gate
S = Source
D = Drain

Either Source terminal of miniBLOC can be used as Main or Kelvin Source

Symbol	Test Conditions	Maximum Ratings		
V_{DSS}	$T_J = 25^\circ\text{C}$ to 150°C	800		V
V_{DGR}	$T_J = 25^\circ\text{C}$ to 150°C ; $R_{GS} = 1 \text{ M}\Omega$	800		V
V_{GS}	Continuous	± 20		V
V_{GSM}	Transient	± 30		V
I_{D25}	$T_C = 25^\circ\text{C}$	34		A
I_{DM}	$T_C = 25^\circ\text{C}$, pulse width limited by T_{JM}	136		A
I_{AR}		34		A
E_{AR}	$T_C = 25^\circ\text{C}$	64		mJ
E_{AS}	$T_C = 25^\circ\text{C}$	3		J
dv/dt	$I_S \leq I_{DM}$, $di/dt \leq 100 \text{ A}/\mu\text{s}$, $V_{DD} \leq V_{DSS}$, $T_J \leq 150^\circ\text{C}$, $R_G = 2 \Omega$	5		V/ns
P_D	$T_C = 25^\circ\text{C}$	600		W
T_J		-55 ... +150		$^\circ\text{C}$
T_{JM}		150		$^\circ\text{C}$
T_{stg}		-55 ... +150		$^\circ\text{C}$
T_L	1.6 mm (0.063 in) from case for 10 s	300		$^\circ\text{C}$
V_{ISOL}	50/60 Hz, RMS $I_{ISOL} \leq 1 \text{ mA}$	t = 1 min t = 1 s	2500 3000	V~
M_d	Mounting torque Terminal connection torque		1.5/13	Nm/lb.in.
M_d			1.5/13	Nm/lb.in.
Weight		30		g

Symbol	Test Conditions	Characteristic Values		
		($T_J = 25^\circ\text{C}$, unless otherwise specified)	min.	typ.
V_{DSS}	$V_{GS} = 0 \text{ V}$, $I_D = 3 \text{ mA}$ V_{DSS} temperature coefficient	800		V
			0.096	%/K
$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 8 \text{ mA}$ $V_{GS(th)}$ temperature coefficient	3.0		V
			-0.214	%/K
I_{GSS}	$V_{GS} = \pm 20 \text{ V}_{DC}$, $V_{DS} = 0$			$\pm 200 \text{ nA}$
I_{DSS}	$V_{DS} = V_{DSS}$ $V_{GS} = 0 \text{ V}$	$T_J = 25^\circ\text{C}$ $T_J = 125^\circ\text{C}$		100 2 mA
$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$, $I_D = 0.5 \cdot I_{D25}$ Pulse test, $t \leq 300 \mu\text{s}$, duty cycle $d \leq 2 \%$		0.24	Ω

IXYS reserves the right to change limits, test conditions, and dimensions.

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Features

- International standard packages
- miniBLOC, with Aluminium nitride isolation
- Low $R_{DS(on)}$ HDMOS™ process
- Rugged polysilicon gate cell structure
- Unclamped Inductive Switching (UIS) rated
- Low package inductance
- Fast intrinsic Rectifier

Applications

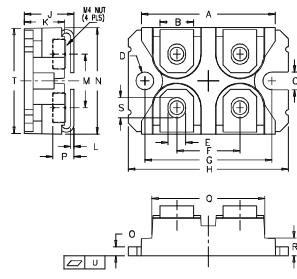
- DC-DC converters
- Battery chargers
- Switched-mode and resonant-mode power supplies
- DC choppers
- Temperature and lighting controls

Advantages

- Easy to mount
- Space savings
- High power density

Symbol	Test Conditions	Characteristic Values		
		($T_j = 25^\circ\text{C}$, unless otherwise specified)	min.	typ.
g_{fs}	$V_{DS} = 10 \text{ V}; I_D = 0.5 \cdot I_{D25}$, pulse test	20	35	S
C_{iss} C_{oss} C_{rss}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$	7500		pF
		920		pF
		220		pF
$t_{d(on)}$ t_r $t_{d(off)}$ t_f	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}, I_D = 0.5 \cdot I_{D25}$ $R_G = 1 \Omega$ (External)	45		ns
		45		ns
		100		ns
		40		ns
$Q_{g(on)}$ Q_{gs} Q_{gd}	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}, I_D = 0.5 \cdot I_{D25}$	270		nC
		60		nC
		140		nC
R_{thJC}			0.22	K/W
R_{thCK}			0.15	K/W
R_{thJC}			0.21	K/W
R_{thCK}			0.05	K/W

miniBLOC, SOT-227 B



Dim.	Millimeter Min.	Millimeter Max.	Inches Min.	Inches Max.
A	31.50	31.88	1.240	1.255
B	7.80	8.20	0.307	0.323
C	4.09	4.29	0.161	0.169
D	4.09	4.29	0.161	0.169
E	4.09	4.29	0.161	0.169
F	14.91	15.11	0.587	0.595
G	30.12	30.30	1.186	1.193
H	38.00	38.23	1.496	1.505
J	11.68	12.22	0.460	0.481
K	8.92	9.60	0.351	0.378
L	0.76	0.84	0.030	0.033
M	12.60	12.85	0.496	0.506
N	25.15	25.42	0.990	1.001
O	1.98	2.13	0.078	0.084
P	4.95	5.97	0.195	0.235
Q	26.54	26.90	1.045	1.059
R	3.94	4.42	0.155	0.174
S	4.72	4.85	0.186	0.191
T	24.59	25.07	0.968	0.987
U	-0.05	0.1	-0.002	0.004

Source-Drain Diode

Characteristic Values

(T_j = 25°C, unless otherwise specified)

Symbol	Test Conditions	min.	typ.	max.
I_s	$V_{GS} = 0 \text{ V}$		34	A
I_{SM}	Repetitive; pulse width limited by T _{JM}		136	A
V_{SD}	$I_F = I_S, V_{GS} = 0 \text{ V}$, Pulse test, t ≤ 300 μs, duty cycle d ≤ 2 %		1.5	V
t_{rr} Q_{RM} I_{RM}	$I_F = I_S, -di/dt = 100 \text{ A}/\mu\text{s}, V_R = 100 \text{ V}$	$T_j = 25^\circ\text{C}$	250	ns
		$T_j = 125^\circ\text{C}$	400	ns
		$T_j = 25^\circ\text{C}$	1.4	μC
			10	A

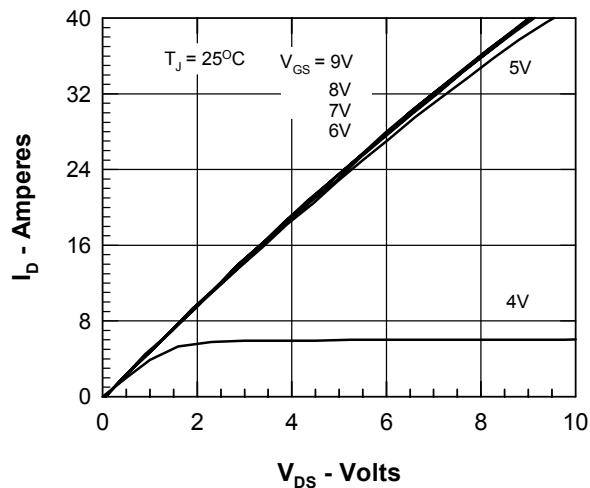


Figure 1. Output Characteristics at 25°C

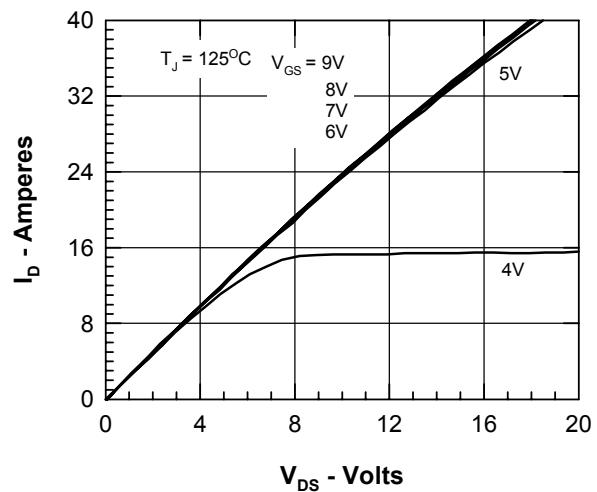


Figure 2. Output Characteristics at 125°C

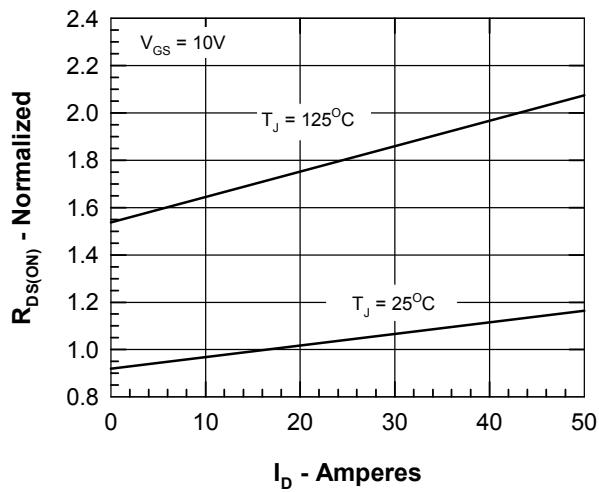
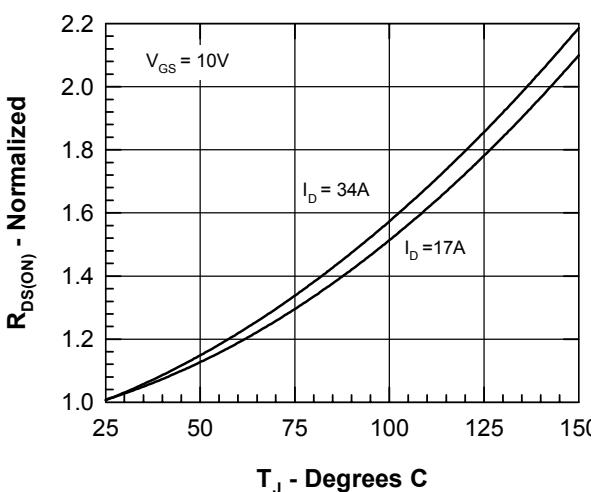
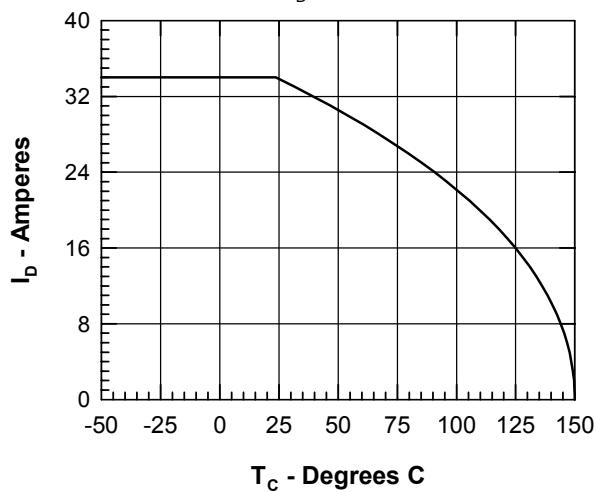
Figure 3. $R_{DS(on)}$ normalized to 0.5 I_{D25} value vs. I_D Figure 4. $R_{DS(on)}$ normalized to 0.5 I_{D25} value vs. T_J 

Figure 5. Drain Current vs. Case Temperature

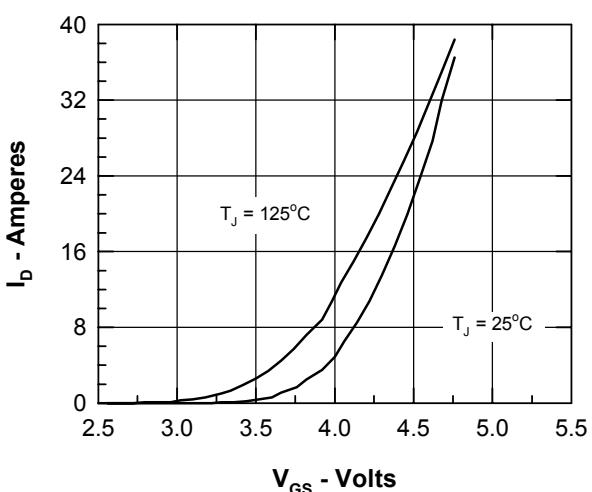


Figure 6. Admittance Curves

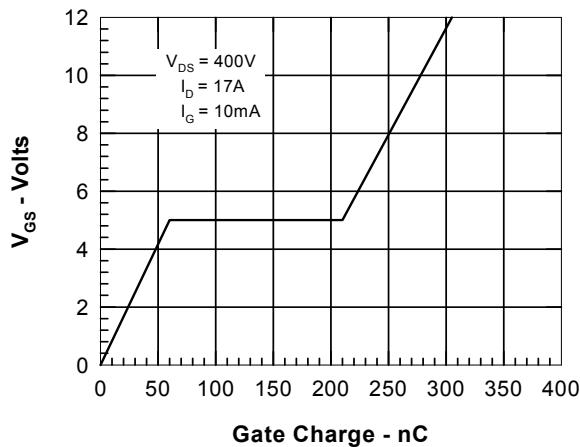


Figure 7. Gate Charge

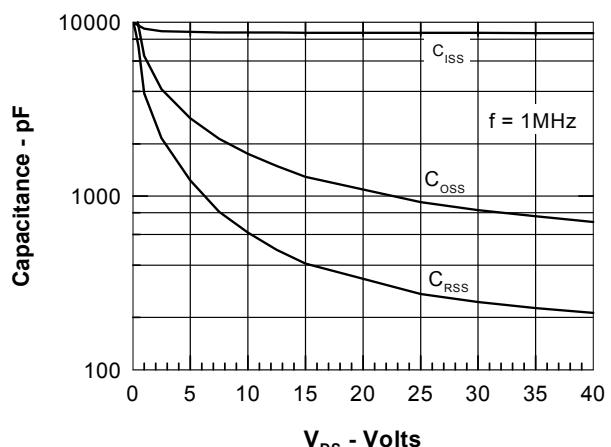


Figure 8. Capacitance Curves

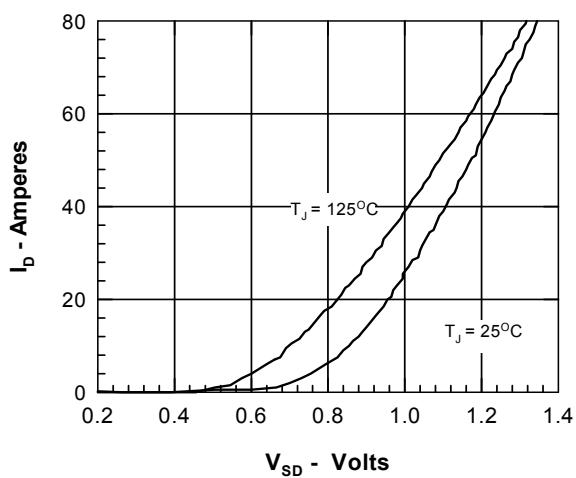


Figure 8. Forward Voltage Drop of the Intrinsic Diode

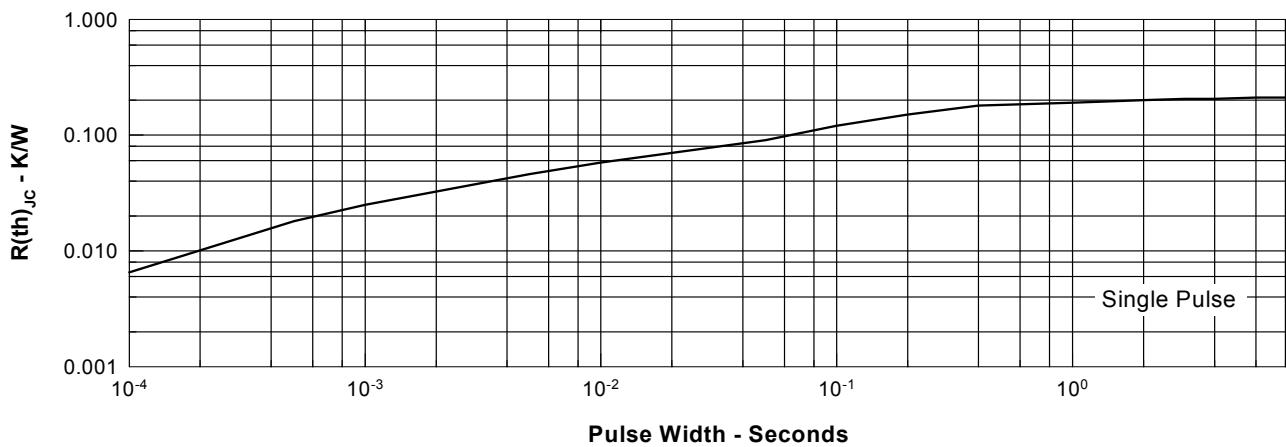


Figure 9. Transient Thermal Resistance



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